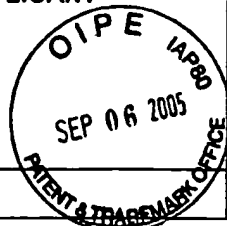


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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Complete if Known

Application Number	09/945,507
Filing Date	August 30, 2001
First Named Inventor	Forbes, Leonard
Group Art Unit	2824
Examiner Name	Dinh, Son

Sheet 1 of 2

Attorney Docket No: 1303.014US1

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
CD	US-2002/0192974	12/19/2002	Ahn, Kie Y., et al.	06/13/2001
	US-2002/0008324-A1	01/24/2002	Shinkawata, H	01/23/2001
	US-2003/0045078-A1	03/06/2003	Ahn, Kie Y., et al.	08/30/2004
	US-2003/0119246-A1	06/26/2003	Ahn, Kie Y.	12/20/2001
	US-2003/0227033-A1	12/11/2003	Ahn, Kie Y., et al.	06/05/2002
	US-2003/0228747	12/11/2003	Ahn, Kie Y., et al.	06/05/2002
	US-2004/0023461-A1	02/05/2004	Ahn, Kie Y., et al.	07/30/2002
	US-2004/0038554-A1	02/26/2004	Ahn, Kie Y.	08/21/2002
	US-2004/0043541-A1	03/04/2004	Ahn, Kie Y.	08/29/2002
CD	US-2004/0043569-A1	03/04/2004	Ahn, Kie Y.	08/28/2002
	US-2004/0110348-A1	06/10/2004	Ahn, Kie Y., et al.	12/04/2002
	US-2004/0110391-A1	06/10/2004	Ahn, K. Y., et al.	12/04/2002
	US-2004/0175882-A1	09/09/2004	Ahn, Kie Y., et al.	03/04/2003
	US-2004/0214399-A1	10/28/2004	Ahn, K. Y., et al.	04/22/2003
	US-2004/0262700-A1	12/30/2004	Ahn, K. Y., et al.	06/24/2003
	US-2005/0020017-A1	01/27/2005	Ahn, K. Y., et al.	06/24/2003
	US-2005/0054165-A1	03/10/2005	Ahn, K. Y., et al.	03/31/2003
	US-2005/0077519-A1	04/14/2005	Ahn, Kie, et al.	10/10/2003
	US-2005/0169054-A1	08/04/2005	Forbes, L.	02/22/2005
CD	US-4,556,975	12/03/1985	Smith, T. B., et al.	02/07/1983
	US-4,672,240	06/09/1987	Smith, T. B., et al.	08/29/1985
	US-5,153,880	10/06/1992	Owen, W. H., et al.	03/12/1990
	US-5,353,431	10/04/1994	Doyle, P. F., et al.	02/08/1994
	US-5,618,761	04/08/1997	Eguchi, K., et al.	09/11/1995
	US-5,619,051	04/08/1997	Endo, N.	06/23/1995
	US-6,495,436	12/17/2002	Ahn, Kie Y., et al.	02/09/2001
	US-6,504,207	01/07/2003	Chen, Bomy A., et al.	06/30/2000
CD	US-6,514,828	02/04/2003	Ahn, Kie Y., et al.	04/20/2001
	US-6,534,420	03/18/2003	Ahn, Kie Y., et al.	07/18/2001
	US-6,574,143	06/03/2003	Nakazato, K.	12/08/2000
	US-6,767,795	07/27/2004	Ahn, K., et al.	01/17/2002
	US-6,790,791	09/14/2004	Ahn, Kie Y., et al.	08/15/2002
	US-6,844,203	01/18/2005	Ahn, K. Y., et al.	08/30/2001
	US-6,884,739	04/26/2005	Ahn, K. Y., et al.	08/15/2002
	US-6,893,984	05/17/2005	Ahn, K. Y., et al.	02/20/2002
CD	US-6,900,122	05/31/2005	Ahn, K. Y., et al.	12/20/2001

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)	Complete if Known	
	Application Number	09/945,507
	Filing Date	August 30, 2001
	First Named Inventor	Forbes, Leonard
	Group Art Unit	2824
	Examiner Name	Dinh, Son
Sheet 2 of 2	Attorney Docket No: 1303.014US1	

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
SN		AHN, KIE Y., et al., "ALD OF AMORPHOUS LANTHANIDE DOPED TIOX FILMS", U.S. Application Serial No. 11/092,072; filed March 29, 2005 (Atty. Dkt. No. 1303.135US1).	
		AHN, KIE Y., et al., "ATOMIC LAYER DEPOSITED HAFNIUM TANTALUM OXIDE DIELECTRICS", U.S. Application Serial No. 11/029,757; filed January 5, 2005 (Atty. Dkt. No. 1303.127US1).	
		AHN, KIE Y., et al., "ATOMIC LAYER DEPOSITED LANTHANUM ALUMINUM OXIDE DIELECTRIC LAYER", U.S. Application Serial No. 10/930,167; filed August 31, 2004 (Atty. Dkt. No. 1303.122US1).	
SN		AHN, KIE Y., et al., "ATOMIC LAYER DEPOSITED LANTHANUM HAFNIUM OXIDE DIELECTRICS", U.S. Application Serial No. 11/010,529; filed December 13, 2004 (Atty. Dkt. No. 1303.126US1).	
		AHN, KIE Y., et al., "ATOMIC LAYER DEPOSITED TITANIUM ALUMINUM OXIDE FILMS", U.S. Application Serial No. 10/931,533; filed August 31, 2004 (Atty. Dkt. No. 1303.119US1).	
		AHN, KIE Y., et al., "ATOMIC LAYER DEPOSITION OF Hf3N4/HfO2 FILMS AS GATE DIELECTRICS", U.S. Application Serial No. 11/063,717; filed February 23, 2005 (Atty. Dkt. No. 1303.134US1).	
		AHN, KIE Y., et al., "ATOMIC LAYER DEPOSITION OF ZIRCONIUM-DOPED TANTALUM OXIDE FILMS", U.S. Application Serial No. 10/909,959; filed August 2, 2004 (Atty. Dkt. No. 1303.114US1).	
		AHN, KIE Y., et al., "ATOMIC LAYER DEPOSITION OF Zr3N4/ZrO2 FILMS AS GATE DIELECTRICS", U.S. Application Serial No. 11/058,563; filed February 15, 2005 (Atty. Dkt. No. 1303.133US1).	
		AHN, KIE Y., et al., "HYBRID ALD-CVD OF PrXOY/ZrO2 FILMS AS GATE DIELECTRICS", U.S. Application Serial No. 11/010,766; filed December 13, 2004 (Atty. Dkt. No. 1303.129US1).	
SN		AHN, KIE Y., et al., "RUTHENIUM GATE FOR A LANTHANIDE OXIDE DIELECTRIC LAYER", U.S. Application Serial No. 10/926,812; filed August 26, 2004 (Atty. Dkt. No. 1303.121US1).	

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